



Nano DS

Dual Scattering Particle Size Analyzer



■ DLS & SLS

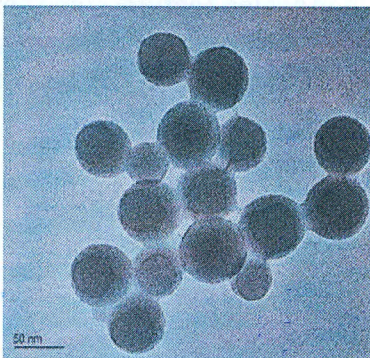
■ Dual Technology

■ Multi-angle DLS

■ Repeatability <1%

■ Maintenance-free design

■ Multi-peak size distribution measurements



63 nm latex particles
(CILAS image)

The new **Nano DS** Dual Scattering Particle Size Analyzer features a breakthrough technology that makes **nanoparticle characterization more accurate** even if your **sample is agglomerated** or has a **multi-peak size distribution**. This is achieved by a combination of **Static Light Scattering (SLS)** and **Dynamic Light Scattering (DLS)** measurement in **one single optical system**. This technology provides you with the best **accuracy, repeatability and resolution** over the entire **0.3 nm to 10 μ m** size range.

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The ultimate in nanoparticle characterization

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Detailed Product Specification Sheet

Nano DS Dual Scattering Particle Size Analyzer

Parameters	Specifications
Particle size range	0.3 nm to 10 µm
Sample concentration	Up to 40% (V)
Repeatability	Better than 1%
Technology	Static & Dynamic Multi angle Laser Light Scattering (SLS & DLS)
Scattering angle	From 10° (front scattering) to 150° (back scattering), angle resolution 0.01°
Light source	Laser Diode @ 638 nm- 25mW
Sample volume	3 mL
Photon counting unit	High sensitive Photon counter based on PMT
Measurement time	30 s to 60 s depending on sample and protocol
Sample setting temperature	25°C
Cuvette Type	Glass cuvette compatible with organic solvents, plastic cuvette
Ambient Temperature	+10 to +40 °C
Warm up time	< 2 min
Product Dimensions	W: 341 mm, H: 218 mm, L: 533 mm
Product Weight	14.5 kg
Shipping Dimensions	W: 500 mm, H: 300 mm, L: 690 mm
Shipping Weight	25 kg
Operating System	Windows 7 32 & 64bits, XP Pro 32 bits
Computer configuration	Compatible with OS, RAM 4 Go, 1 port USB 2.0 for the device
Power supply	115V/60Hz – 230V/50Hz, 60W
Analysis Software NanoExpert	Performs multi-acquisition at user defined angles. Features cumulant, Contin inversion algorithms, size distribution, Integrated Database for SOP and results management, export to Excel and PDF format, user account management.
Metrology Std.	Compliance with CFR21part11, ISO 13320 and 13321, ISO 22412:2008
Laser Safety classification	Class I compliant EN 60825-1:2008 & 21 CFR-1040
EC regulatory std.	EMC : directive 2004-108/EC Electrical Safety : directive 2006/95/EC
Delivered with	USB 2.0 cable, NanoExpert software.
CRM kit (optional)	NIST traceable 100 nm latex spheres sample for periodic verification

All performances are sample dependent

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